

Synthesis of Y-Ba-Cu-O thin films by laser annealing

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Developing high-temperature superconducting films with superior critical properties is an extremely important problem. The synthesis of superconducting films of perovskite ceramics by a variety of methods has been reported in several papers.^{1,2} Better results have been achieved for films of the Y-Ba-Cu-O system. The temperature at which the superconducting transition begins is $T_C = 94$ K, the width of this transition is $\Delta T_C \approx 10-30$ K, and the critical current density is $J_C \approx 10^3$ A/cm². The apparent reason for the large value of ΔT_C and the low values of J_C is that the compounds which have been synthesized are imperfect and contain other - nonsuperconducting - phases. In addition, the methods used to synthesize the superconducting films in Refs. 1 and 2 are of limited applicability because of two serious drawbacks: 1) The films must be subjected to high-temperature annealing at ~600-900°C after they are deposited. This requirement is incompatible with semiconductor technology in most cases. 2) The films having the critical properties specified above were synthesized primarily on SrTiO₃ substrates, although this material is not widely used.

In this paper we report the synthesis of thin (≤ 1 μ m) superconducting films of the compound Y₁Ba₂Cu₃O₇ with $T_C \approx 96-102$ K and with a superconducting width $\Delta T_C \leq 3$ K. The superconducting films were synthesized by the laser annealing of the surface of a sample consisting of a finely disperse mixture of oxides of yttrium, barium, and copper. The finely disperse stock material was prepared by a chemical method.³ The nitrates of barium, copper, and yttrium were dissolved in nitric acid in the required stoichiometric proportions of the components Y, Ba, and Cu. After evaporation of the solutions and deposition, the resulting mixture was annealed in air at ~900°C for several hours. The results of chemical, x-ray, and thermal analyses showed that the finely disperse mixture obtained as a result consists of the oxides of Y, Ba, and Cu in which these components are present in the gives stoichiometry. From this mixture we pressed tablets 5.0 mm in diameter and ~1 mm thick. The surfaces of the resulting tablets were subjected to laser annealing, which produced a thin (≤ 1 μ m) superconducting layer of the compound Y₁Ba₂Cu₃O₇.

The laser annealing was carried out in an oxygen atmosphere by running a laser beam 200 μ m in diameter (at the 1/e level) in a raster over the surface of the tablet at a scan step of 50 μ m. The length of the laser pulse at half-maximum was 50 ns, and the wavelength of the light was $\lambda = 1.06$ μ m. The radiant energy density was varied over the range 0.01-1.00 J/cm².

To obtain the required stoichiometry in the resulting film, we carried out the laser annealing in an oxygen atmosphere at pressures up to 100 atm.

The superconducting transition was detected from the change in the relative magnetic suscepti-

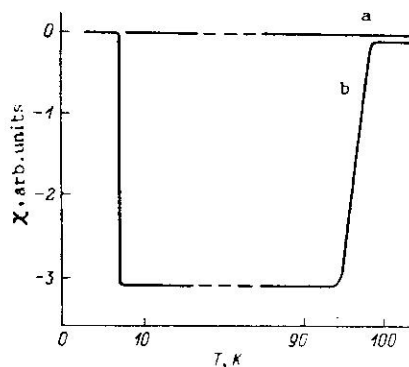


FIG. 1. Relative magnetic susceptibility versus the temperature: a) Before; b) after laser annealing.

bility χ_{rel} as the temperature was varied. The frequency and amplitude of the modulating magnetic field were 41 Hz and 30 Oe, respectively. The sample temperature was measured in the range 4.2-300 K by a TSU-1 carbon resistance thermometer to within 0.5 K. The diamagnetic response of the test sample was compared with that from a sample of known geometry, positioned in a compensating coil.

Fig. 1 shows the relative magnetic susceptibility versus the temperature for the films of the Y-Ba-Cu-O system which we synthesized. The jump in χ_{rel} at 7.2 K (Fig. 1) is a consequence of the superconducting transition of the lead, normalized to a thickness of 1 μ m. The temperature at which the superconducting transition begins for these Y-Ba-Cu-O films was 98 K. The width of the superconducting transition between the levels 0.1 and 0.9 of χ_{max} was 3 K. Also shown in this figure is a plot of χ_{rel} versus the temperature for a tablet which was not subjected to laser annealing (line 'a').

An estimate of the diffusion range l_{diff} of the components of the stock material for these laser-annealing conditions yields $l_{diff} \approx 0.1$ μ m. This figure is an order of magnitude greater than the dimensions of the CuO, BaO, and Y₂O₃ crystallites in the finely disperse stock material. According to the comments above and a comparison of the amplitudes of the diamagnetic response from lead with the Y-Ba-Cu-O film (Fig. 1) suggest that this Y-Ba-Cu-O film has a high concentration of the Y₁Ba₂Cu₃O₇ superconducting phase. In several cases we obtained samples in which the superconducting transition began at 102 K. The critical current density J_C measured at 77 K in a zero magnetic field was not less than (5-8) $\cdot 10^3$ A/cm² for the better samples. The values cited for J_C here are lower estimates, since we were not able to determine the thickness of the resulting superconducting film on the tablet very accurately, and we were not able to achieve a reliable ohmic contact with the test samples.

this study has shown that it is possible to synthesize high-temperature superconductors by the method of laser annealing of a finely disperse stock material. This method will make it possible to produce thin films of high-temperature superconducting and insulating materials. The deposition of a finely disperse material on various substrates is a problem which has not been solved.

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Raman spectroscopy of surface centers in silicon in metal-oxide-semiconductor structures

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Raman spectra of metal-oxide-semiconductor structures on a silicon surface reveal an emission electron-hole pairs which are bound with a surface charge layer (the S line^{1,2}). At a high charge density n_s the surface pairs exist in the form of a two-dimensional (2D) plasma with separate electron and hole layers. The position of the S line is determined in this case by the depth of the Fermi level of the 2D plasma in the surface-charge layer and by the energy of the electron-hole correlation interaction (3) meV (Ref. 1). At low values of n_s the surface pairs exist in the form of excitons with a surface-charge layer.³

In the present experiments on a number of structures on the (100) surface of phosphorus-doped silicon we have observed a new line on the long-wavelength side of the S line in the spectrum. This new line comes from the radiative recombination of electrons and holes which are localized at surface centers (the D line; Fig. 1). As the gate voltage is increased, this new line arises after a certain threshold is reached during the formation of an inversion space-charge layer. This spectral position of the D line is determined by the depth of the Fermi level of the 2D electrons in the quantum well and by the binding energy of a hole at a surface center. At a low density of two-dimensional electrons the binding energy of a hole at a surface center is about 45 meV, and the spectral peak of the D line lies 25 meV lower in energy than the spectral line of an exciton bound to a neutral donor (phosphorus). As n_s increases, this line shifts in the long-wavelength direction because of an increase in the depth of the electron Fermi level in the quantum potential well. At low values of n_s the spectral width of the D line is determined by the width of the band of hole energy levels in the inversion band bending region near the surface and by fluctuations of the surface potential. The spectral width in this case is substantially greater than the thermal energy of the 2D electrons. At large values of n_s , its spectral width becomes approximately the same as the Fermi energy of the 2D electrons, and it increases with increasing n_s .

and holes we observe a short-wavelength shift of the D line with increasing excitation level. This shift is approximately equal to $\Delta E_D = 4 \pi e^2 \epsilon_0^{-1} n_p Z_d/2$, where n_p is the density of localized holes, $Z_d/2$ is the average distance from the surface to the holes, ϵ_0 is the dielectric constant of the silicon, and e is the charge of an electron. By determining

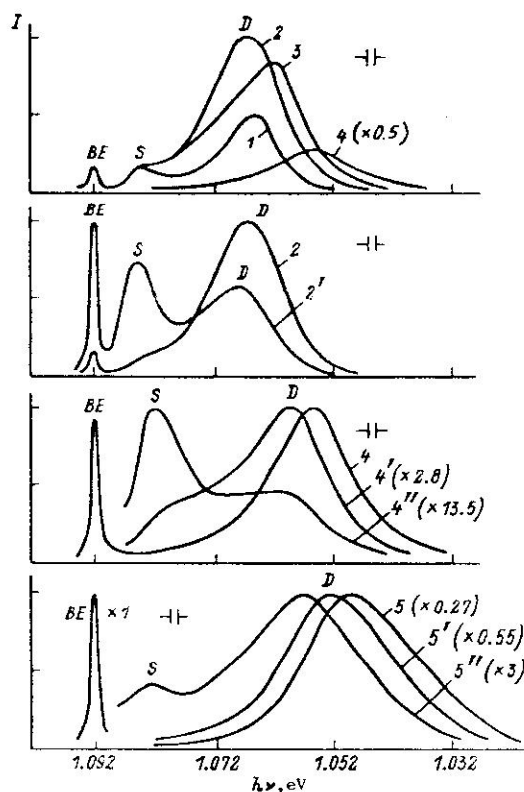


FIG. 1. Recombination radiation spectra of silicon at $T = 1.9$ K (MOS structure; Si:P with a donor density $\sim 3 \cdot 10^{15} \text{ cm}^{-3}$; TO-LO lines). The electron densities in the channel, n_s , are, in units of 10^{12} : 1) 0.07; 2, 2') 0.3; 3) 0.54; 4-4'') 1.47; 5-5'') 3.35. The excitation level, in units of W/cm^2 , is: 1-5) 10^{-3} ; 2'-5') 10^{-2} ; 4'', 5'') 10^{-1} .

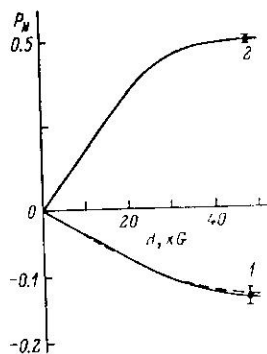


FIG. 2. Degree of circular polarization of the recombination radiation of silicon, P_N , versus the magnetic field H at $T = 1.9$ K. 1) TO-LO-D line, $h\nu = 1.071$ eV, $n_S = 5.4 \cdot 10^{11}$ cm^{-2} ; 2) TO line of a bound exciton (BE), $h\nu = 1.092$ eV. The excitation level is $5 \cdot 10^{-3}$ W/cm^2 .

the nonequilibrium hole density n_p from measurements of the short-wavelength shift of the S line in the case of a (100) hole layer,⁴ and also using Δn_p , we find the average distance from the surface to the localized holes to be $Z_d/2 - (2-3) \cdot 10^{-6}$ cm. In this case the maximum short-wavelength shift corresponds to completely filled surface centers with a density $n_d = n_p \sim 10^{10}$ cm^{-2} . We suggest that these surface centers are boron acceptor atoms. An excess boron concentration ($\sim 10^{16}$ cm^{-3}) may arise near the surface during the deposition of the semitransparent metallic gate of boron-doped polycrystalline silicon on the oxide. When the emission is detected along the direction perpendicular to the surface, we observe in the Faraday geometry (Fig. 2) circular polarization of the LO-D emission line, due to the orientation of the heavy holes in the magnetic field. The energy level of the light holes is split off by the surface electric field and does not contribute to the emission. The TO-D emission line is unpolarized in a magnetic field because of the orbit-valley splitting of the states of the 2D electrons. The average degree of circular polarization of the resultant TO-LO-D emission line is

$$P_N = I_{LO} / (I_{LO} + I_{TO})^{-1} \tanh(3g_1 \mu_0 H / 2kT),$$

where $I_{LO}/I_{TO} = 0.14$, μ_0 is the Bohr magneton, H is the magnetic field, kT is the temperature, and $g_1 = 0.6$ is the g-factor of the holes. The degree of polarization of the emission is essentially independent of the excitation level and of n_S . It reaches a maximum at the short-wavelength edge of the line in the region of the maximum contribution of the LO emission line. The absence of quenching of the TO-D line in a magnetic field at large values of n_S is evidence of a pronounced mixing of the hole states with angular momenta $\pm 3/2$ and $\pm 1/2$. When the emission is detected in a direction parallel to the surface, the TO-D line in the absence of a magnetic field is polarized along the surface with a degree of linear polarization $(I_{\parallel} - I_{\perp}) / (I_{\parallel} + I_{\perp}) = 0.30$, confirming the conclusion regarding the 2D nature of the electrons. The decrease in the intensity of the D line with increasing n_S (Fig. 1) may be a consequence of a decrease in the overlap of the electron and hole wave functions as a result of a decrease in the radius of the wave function of the 2D electrons.

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Breakup of an individual solid particle in a collision with the surface of a moving object

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The supersonic flow of a dust-containing gas around a blunt object was studied experimentally in Refs. 1 and 2. The investigators observed the formation of a zone of elevated concentration of the disperse phase near the shock layer. It has been suggested that this effect is a consequence of the breakup of solid particles in collisions with the surface. In an effort to refine the model which has been proposed for the formation of a zone of elevated concentration of the solid phase, we have now carried out experiments on the collision of individual particles with a plane surface.

According to our estimates, most of the fragments which result from the breakup are less than

10 μm in size. It follows that in order to measure the velocities of the fragments we should provide their slowing in the gaseous medium. The collision of solid particles with surfaces were accelerated by means of a gas jet; the maximum collision velocity was ~ 100 m/s.

To carry out some similar studies we used a ballistic method, which make it possible to isolate the gas from influencing the motion of the particles and to study the collision process at velocities ~ 850 m/s. We studied the collision of a falling solid particle with an object hurled by a rotary accelerator. The samples were incandescent steel cylinders whose leading edge was cut